


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/624,765	MEYERS ET AL.	
Examiner	Art Unit		
Shengjun Wang	1617		

SEARCHED			
Class	Subclass	Date	Examiner
514	570	10/22/2007	SW

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR